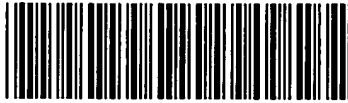


Search Notes

Application/Control No.

10/805,890

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

NALLAN ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	58	12/20/2006	BT
216	68	12/20/2006	BT
216	89	12/20/2006	BT
438	722	12/20/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT, IBM_TDB databases	12/20/2006	BT